

Analog Integrated Systems Design

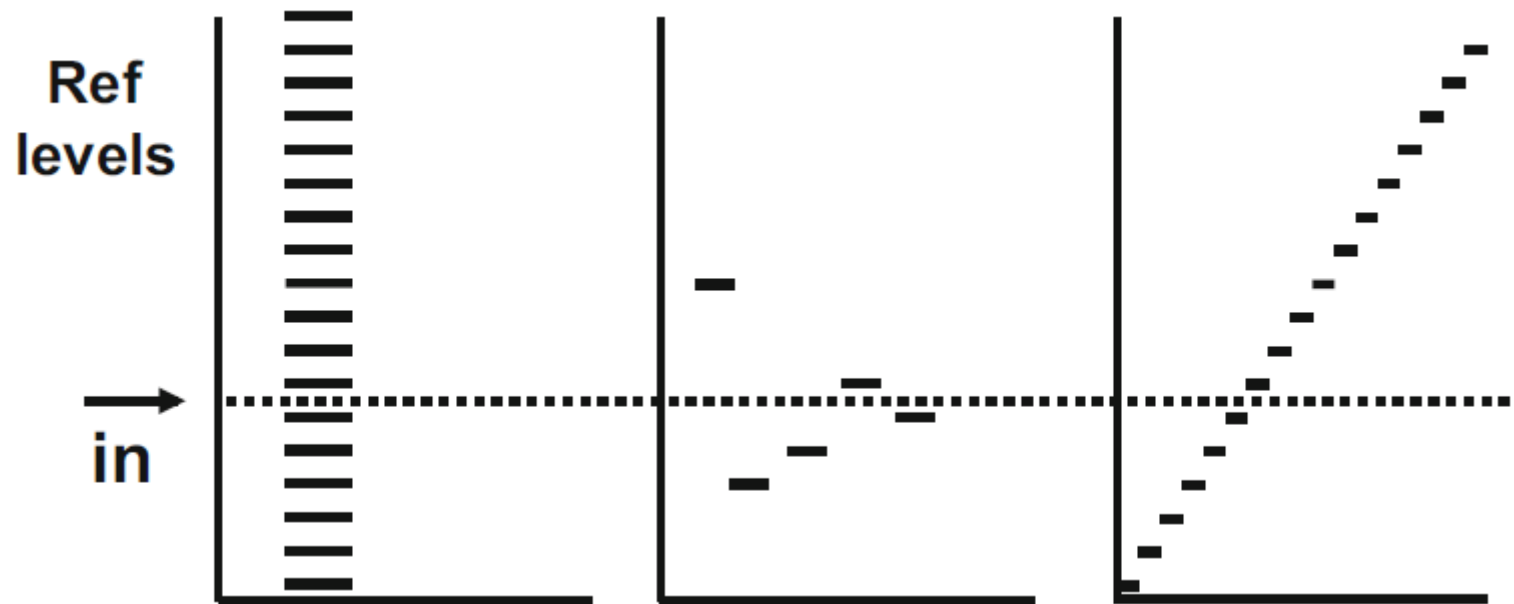
Lecture 13 Nyquist ADCs (2)

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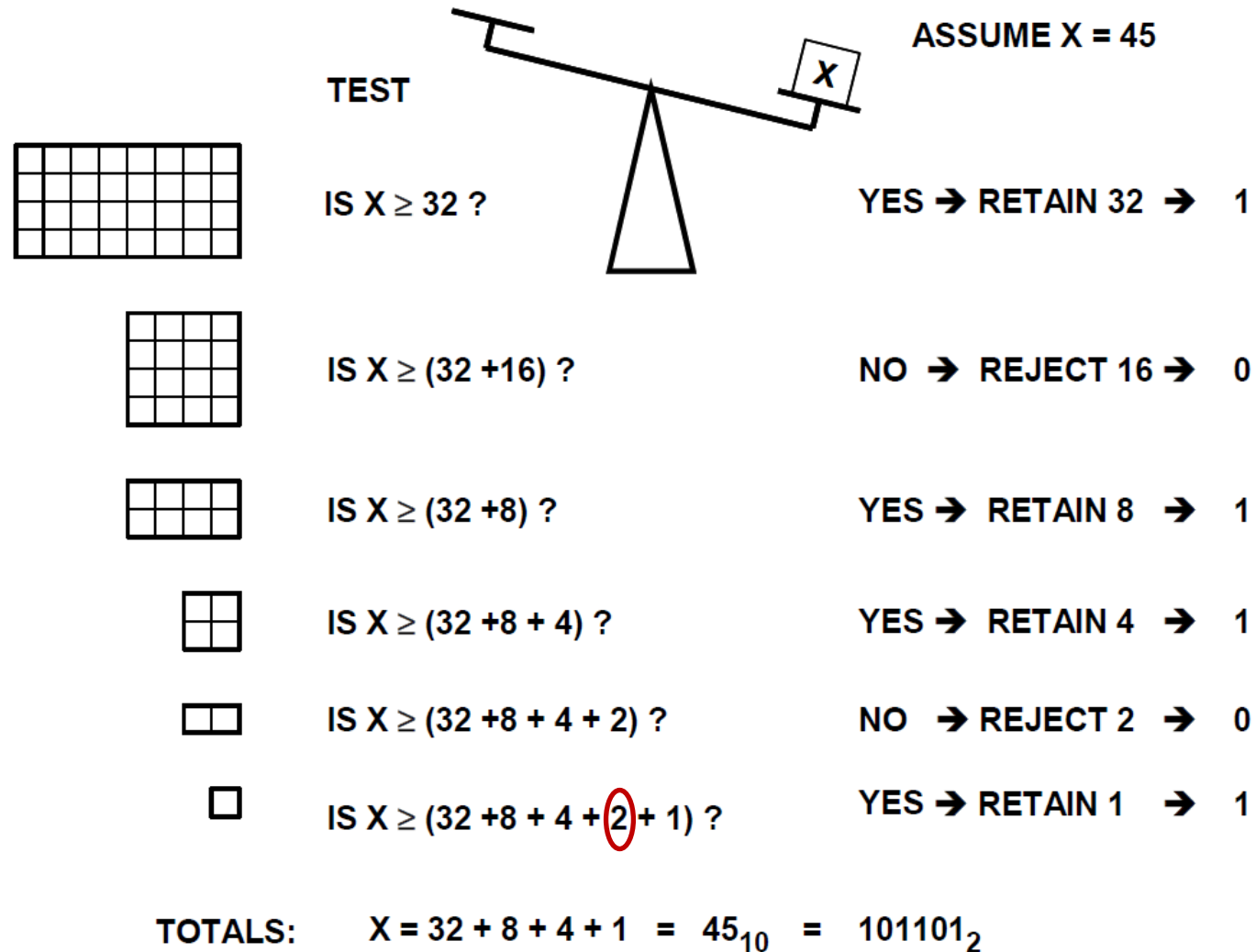
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ADCs Classification

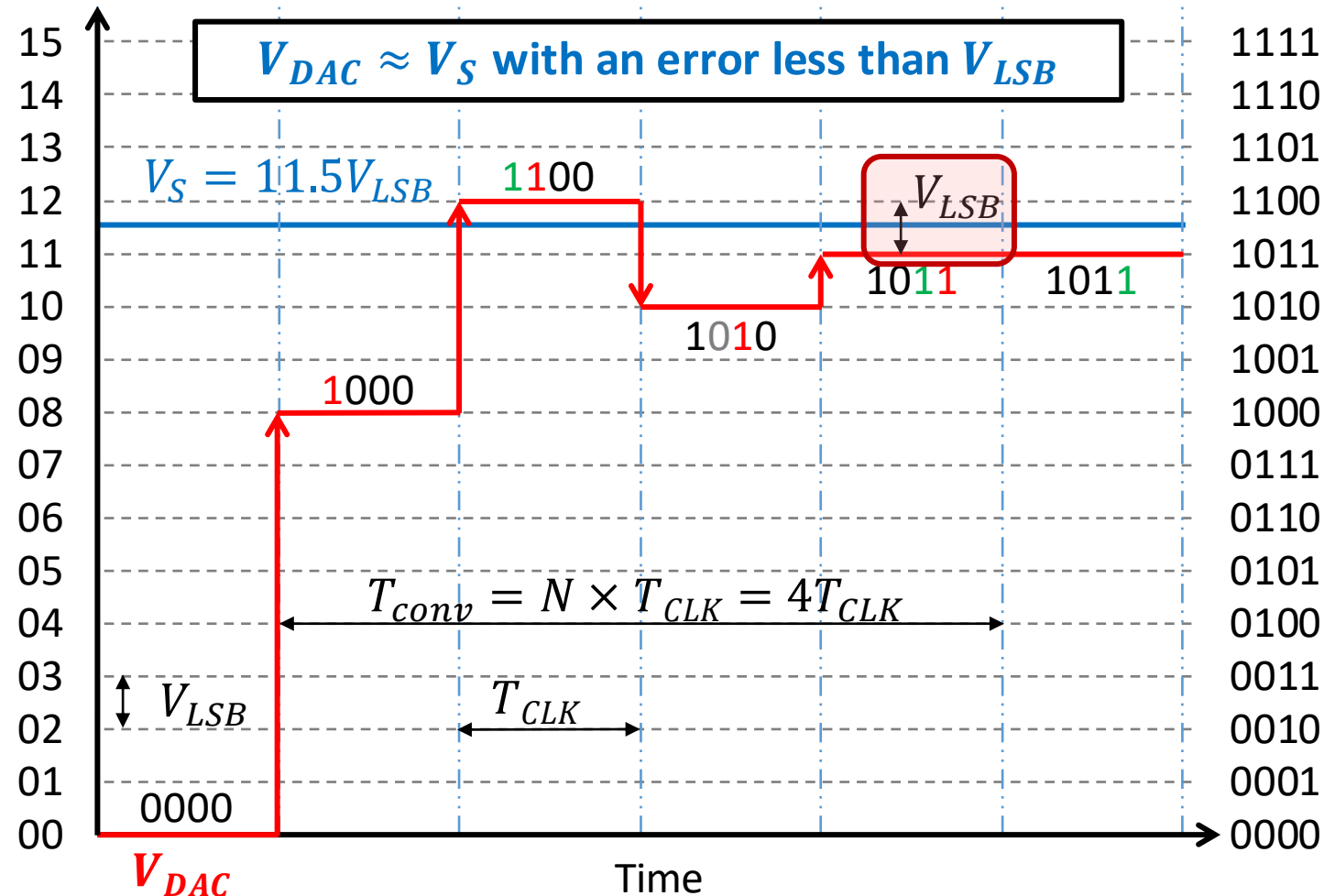
- ❑ Nyquist ADCs: signal BW close to Nyquist limit ($f_s/2$)
 1. Parallel search (e.g., flash ADC): $T_{conv} \sim T_{clk}$
 2. Sequential search (e.g., SAR ADC): $T_{conv} \sim N \times T_{clk}$
 3. Linear search (e.g., dual-slope ADC): $T_{conv} \sim 2^N \times T_{clk}$



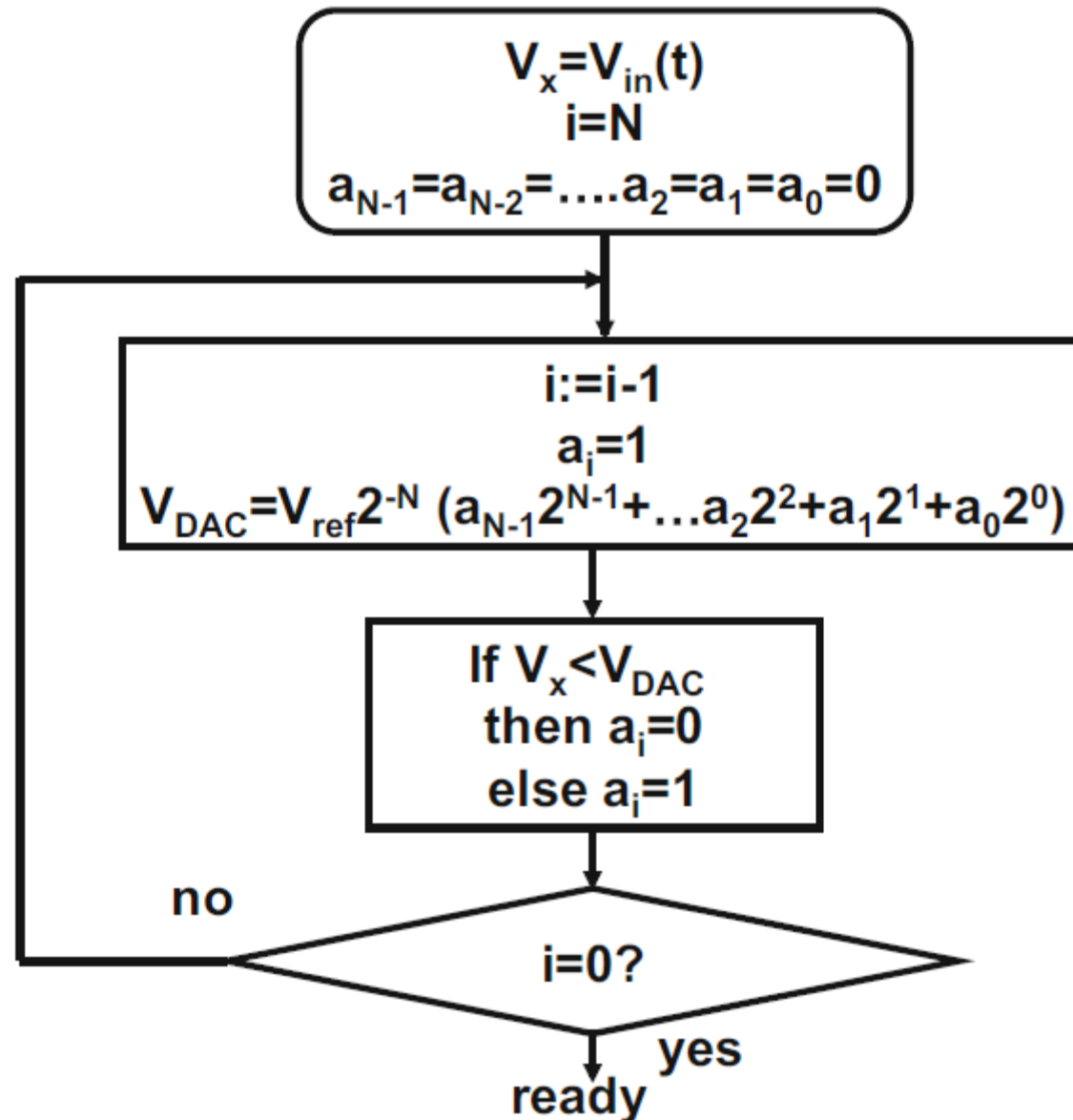
Successive Approximation Algorithm



Successive Approximation Example

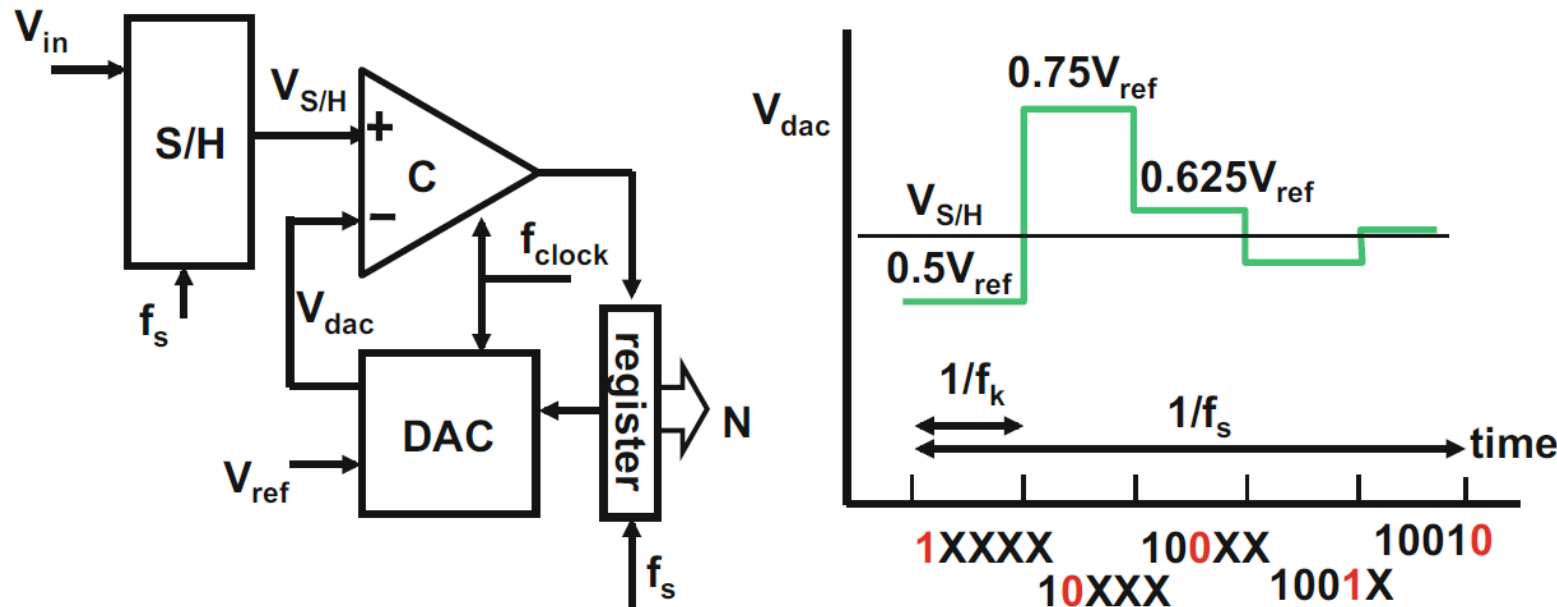


Successive Approximation Flowchart



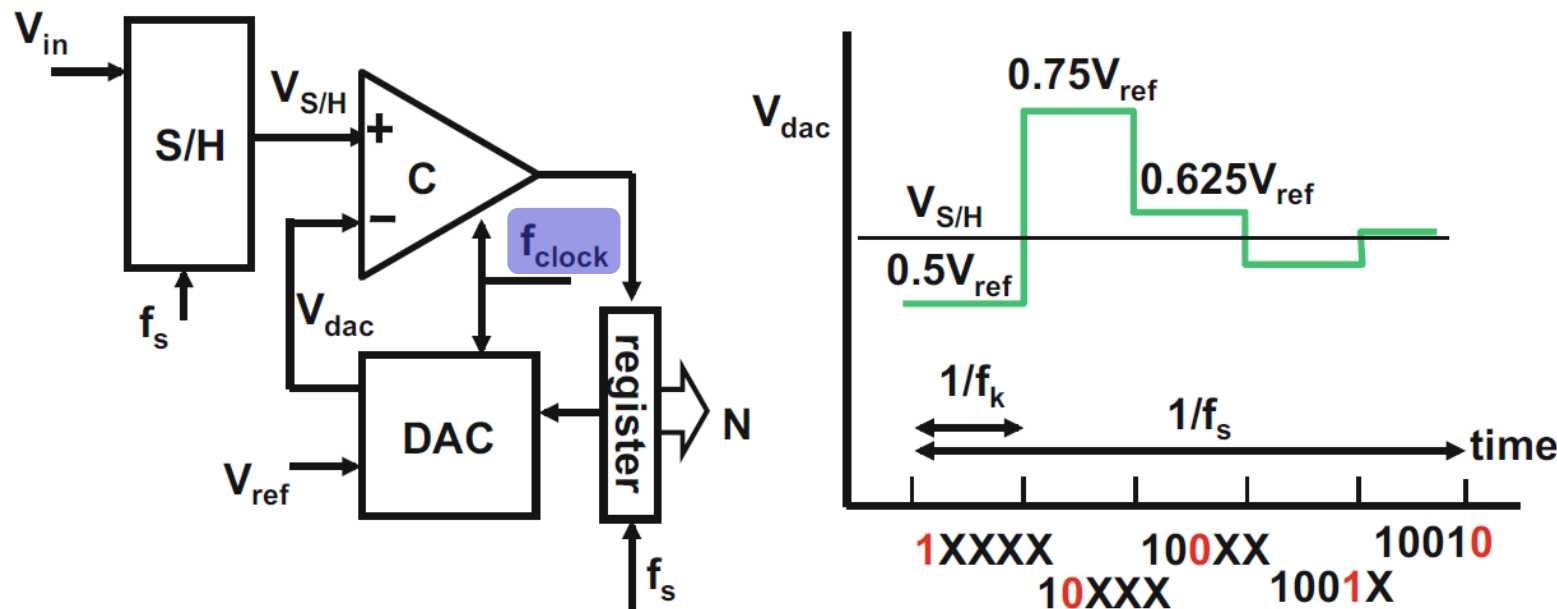
SAR ADC Example

- ❑ SAR stands for successive approximation register
- ❑ Offsets in the sample-and-hold circuit or the comparator will generate a shift of the conversion range
 - But this shift is identical for every code \rightarrow ADC offset error (no non-linearity)
- ❑ Comparator differential input gradually approaches zero
 - Negative feedback loop action



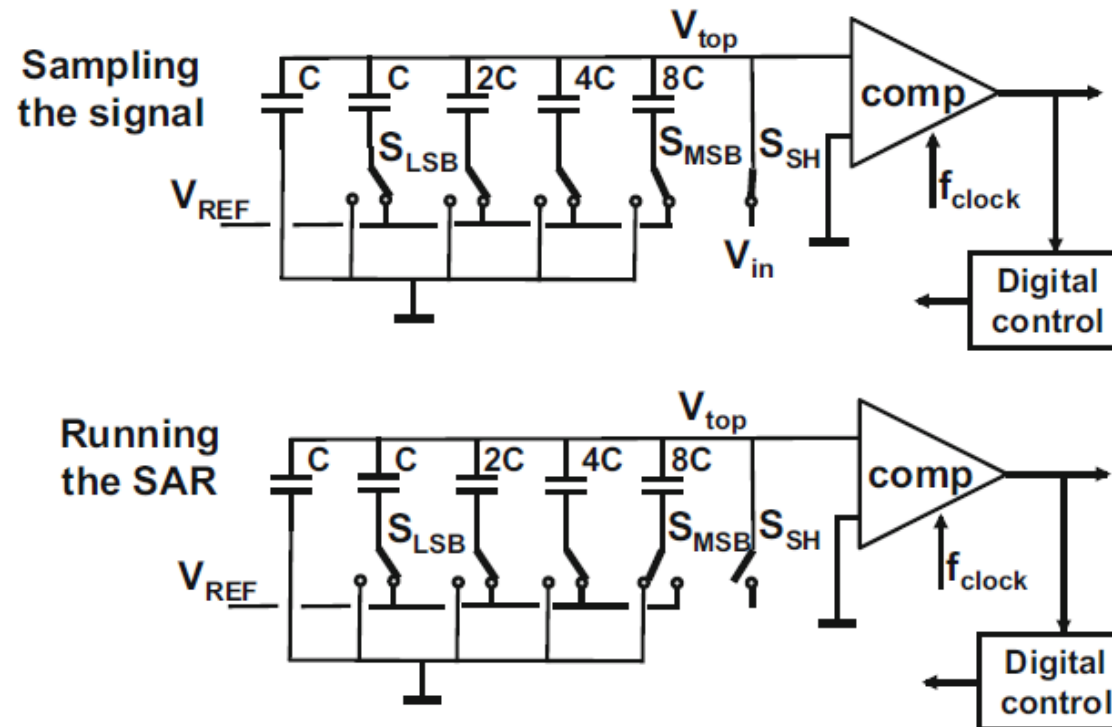
Asynchronous SAR ADC

- ❑ Usually, half T_{clk} is allocated for the DAC and half for the comparison + digital logic
- ❑ The synchronous logic can be replaced by asynchronous logic
 - Event-driven: Each decision triggers next comparison
 - Self-clocked: No high speed external clock is required
 - Example: P. J. A. Harpe *et al.*, *IEEE JSSC*, July 2011.



Charge-Redistribution SAR ADC

- ❑ SAR ADC can be built with any DAC architecture
 - But most attention is focused on capacitive DAC structures
 - Low-power and low-voltage operation
 - The properties of CMOS technology are optimally utilized
 - Good switches and capacitors



Charge-Redistribution SAR ADC

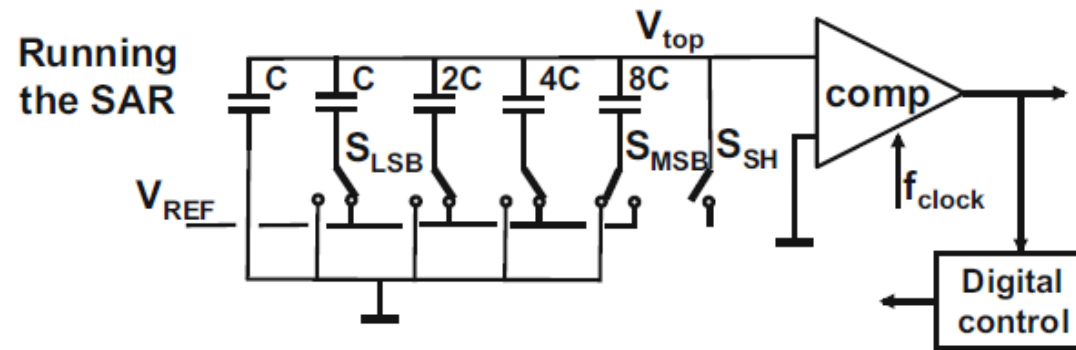
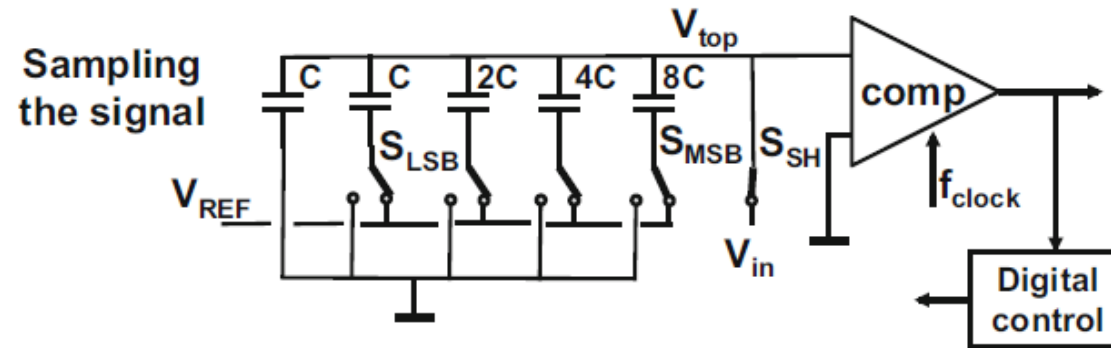
- ❑ Sampling: $Q = (C_{FS} - C)(V_{in} - V_{REF}) + CV_{in}$
- ❑ Conversion: $Q = (C_{on} + C)V_{top} + C_{off}(V_{top} - V_{REF})$

$$C_{FS}V_{in} - (C_{FS} - C)V_{REF} = C_{FS}V_{top} - C_{off}V_{REF}$$

$$V_{top} = V_{in} - \frac{C_{on}}{C_{FS}} V_{ref}$$

$$C_{FS} = 16C$$

$$C_{FS} = C_{on} + C_{off} + C$$



Parasitic Capacitor Effect

❑ The parasitic capacitor at the top plate attenuates V_{REF}

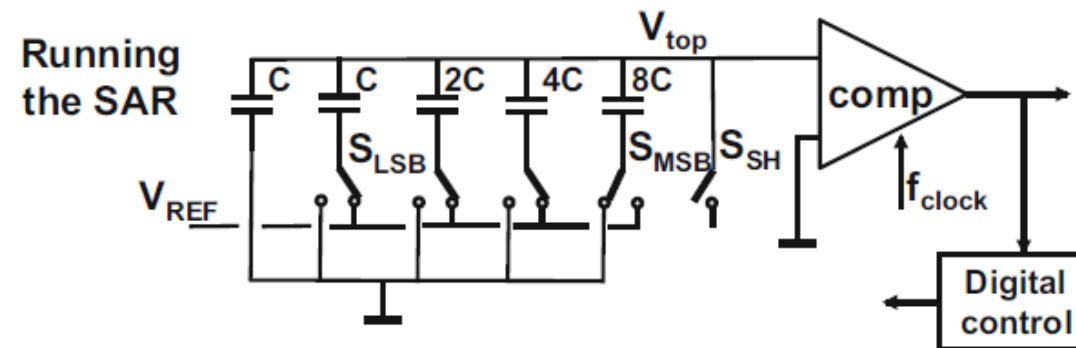
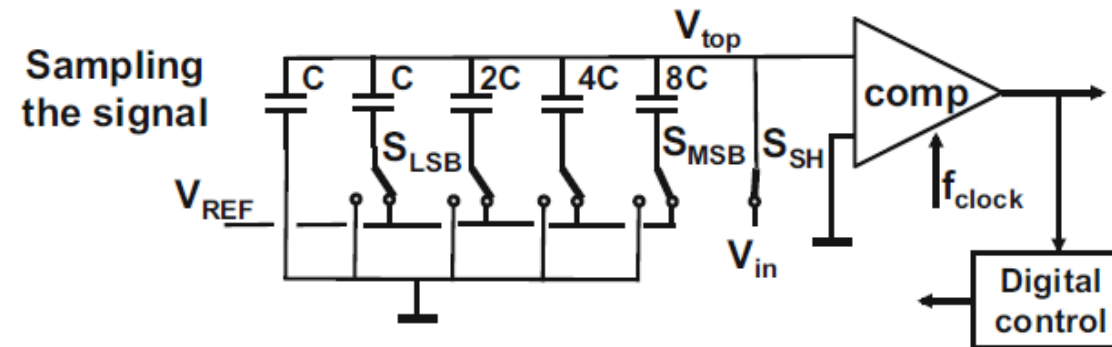
❑ Sampling: $Q = (C_{FS} - C)(V_{in} - V_{REF}) + (C + \mathbf{C_p})V_{in}$

❑ Conversion: $(C_{on} + C + \mathbf{C_p})V_{top} + C_{off}(V_{top} - V_{REF})$

$$V_{top} = V_{in} - \frac{C_{on}}{C_{FS} + C_p} V_{REF} = V_{in} - \frac{C_{on}}{C_{FS}} V'_{REF}$$

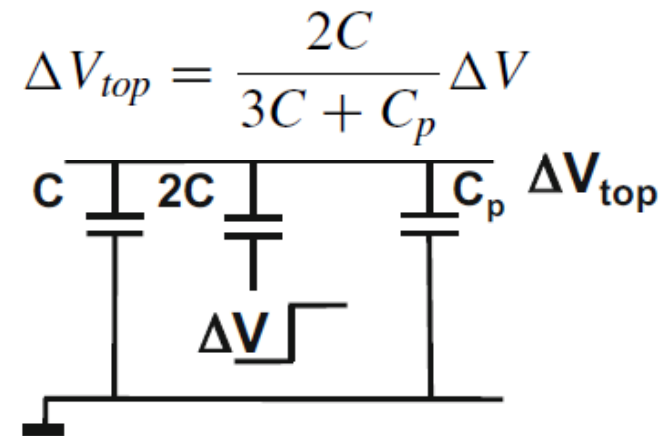
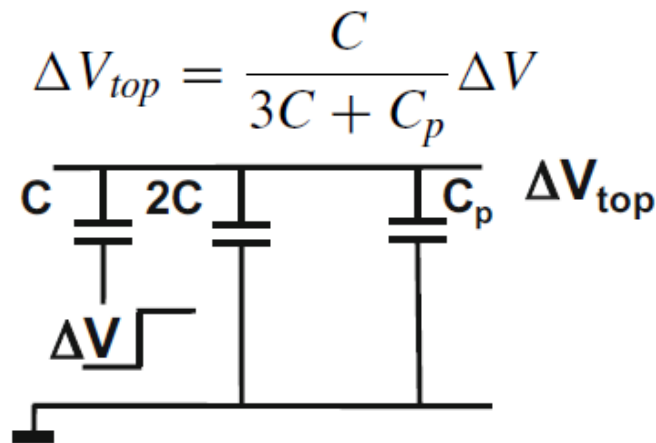
$$V'_{REF} = \frac{C_{FS}}{C_{FS} + C_p} V_{REF}$$

$$V'_{REF} < V_{REF}$$



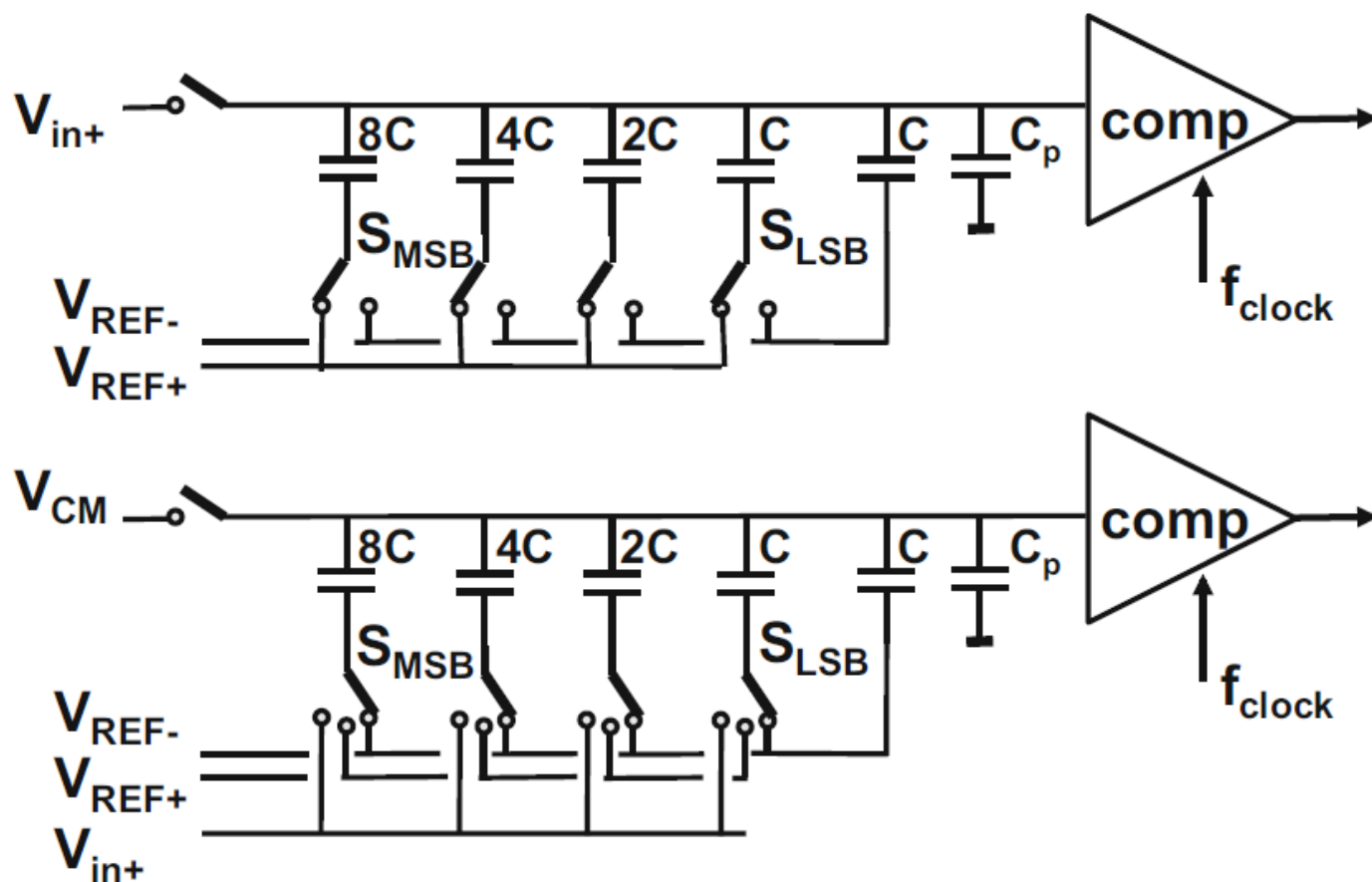
Parasitic Capacitor Effect

- ❑ The voltage step on a capacitor $2C$ gives exactly two times amplitude change on the top plate compared to the same step on a capacitor C
 - Irrespective of the parasitic capacitance.
 - The effect of additional capacitive load on the top plate is just attenuation.
 - But non-linear comparator input capacitance may yield a non-linear error.



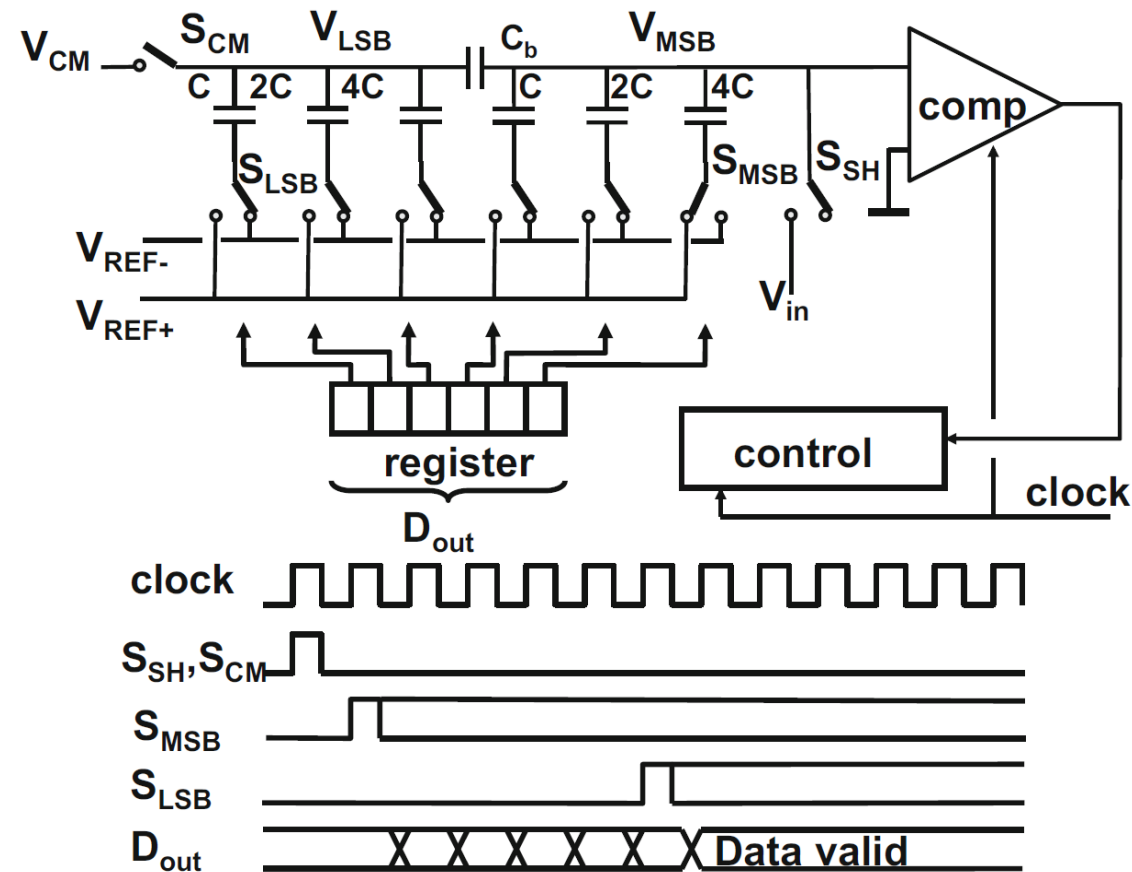
Top vs Bottom Plate Sampling

- ❑ Top: V_{in} does not utilize the full reference range because V_{REF} gets attenuated + input-dependent switching errors (distortion)
- ❑ Bottom: Same path for V_{in} and V_{REF} , but additional V_{CM} is required



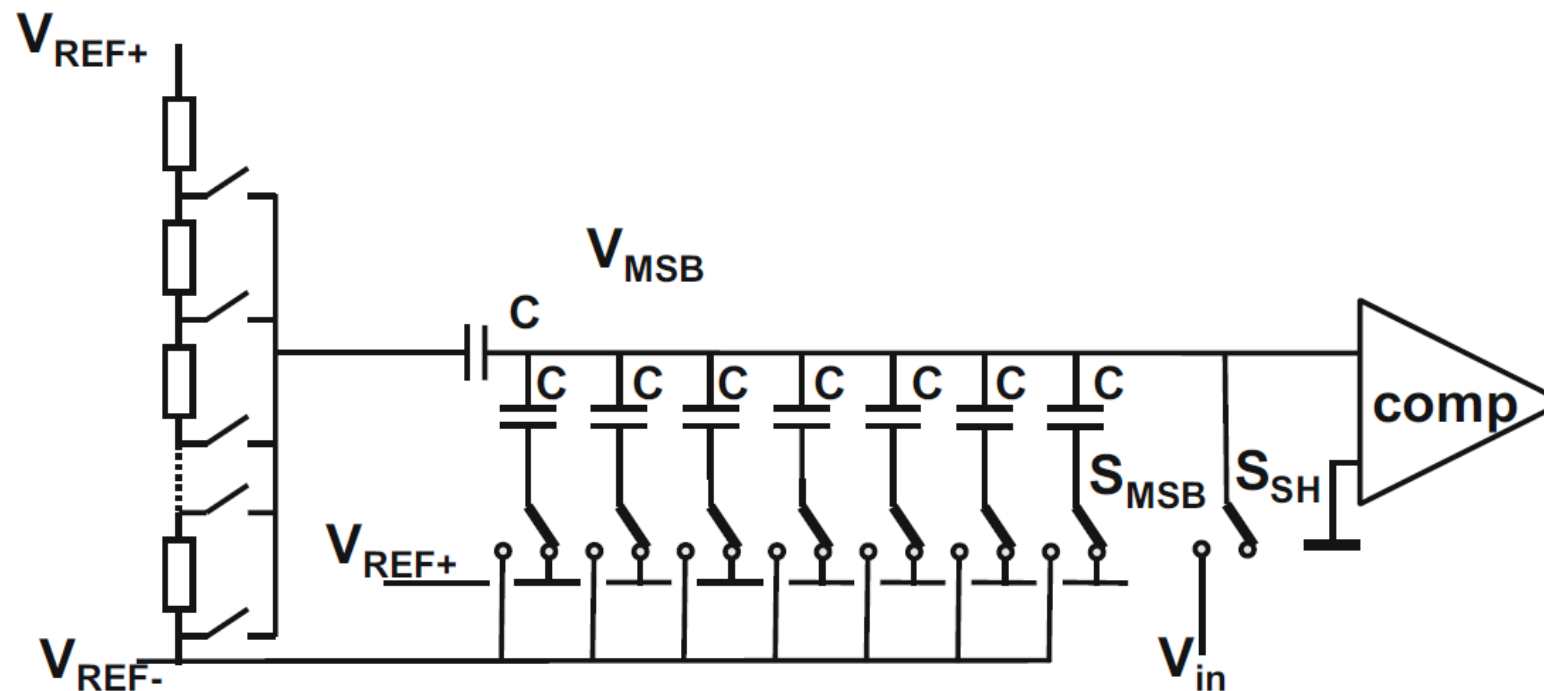
SAR ADC with Bridge Capacitor

- ❑ The LSB section generates a voltage division on the left side of the bridge capacitor
 - But the top node is not a virtual ground node (compare with the DAC lecture)
 - An example of a coarse-fine structure



SAR ADC with Resistor Ladder

- Better coarse-fine operation
 - But the ladder consumes static current



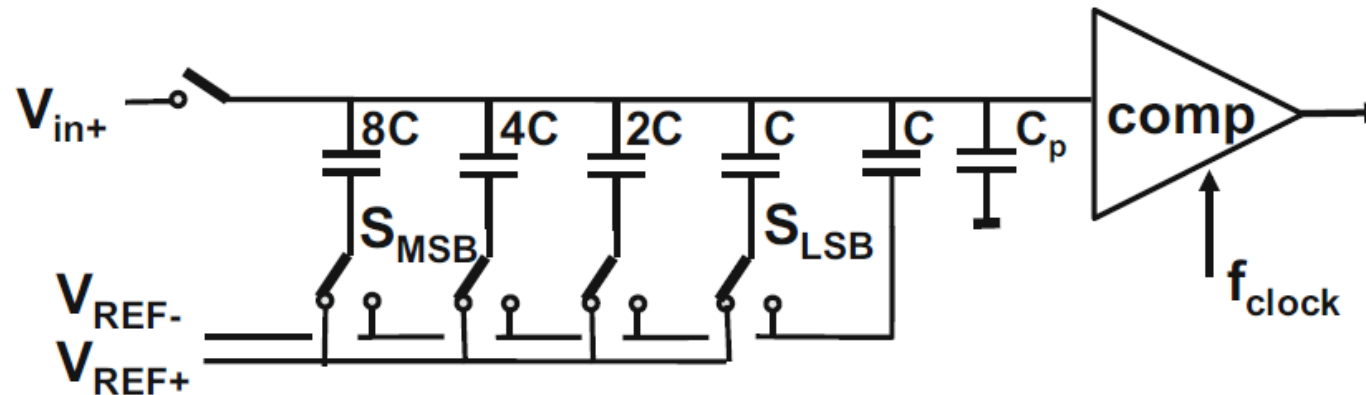
SAR ADC Speed

- ❑ Capacitive DAC has to settle to 0.5 LSB accuracy

$$t_{settle} > 0.69(N + 1)\tau_{DAC}$$

- Switch resistance and output impedance of V_{REF} have to be low
- Switches are scaled for the cap they drive to make τ of each cap nearly constant

- ❑ Comparator speed depends on topology, power consumption, and technology node

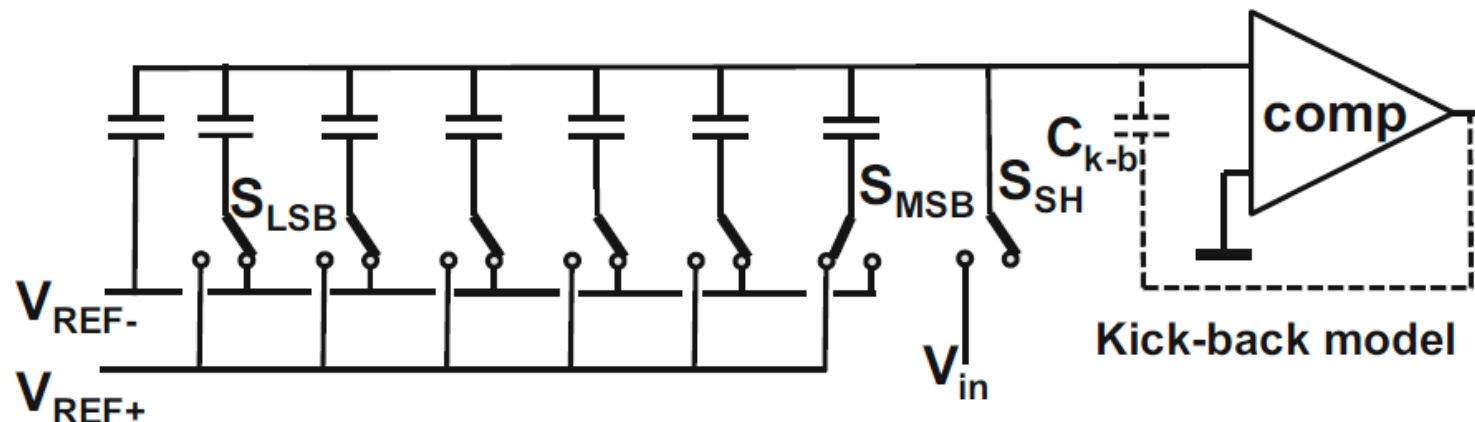


SAR ADC Error Sources

- ❑ Thermal noise of the sampling cap array: kT/C_{FS}
 - Usually small for practical values of C_{FS}
- ❑ Comparator input referred noise
 - Can be reduced by majority voting
- ❑ Sampling clock jitter SNR: $1/(\omega_{in}\sigma_{jitter})^2$
 - High-speed clock buffers consume significant power
- ❑ Quantization error: $V_{LSB}^2/12$
- ❑ Cap array mismatch: Random (A_p/\sqrt{Area}) and systematic (layout) errors
- ❑ Voltage reference errors
 - A good V_{REF} circuit may consume more power than the SAR ADC!
- ❑ Comparator metastability
 - Happens at most once during each conversion
- ❑ Kickback noise (next slide)

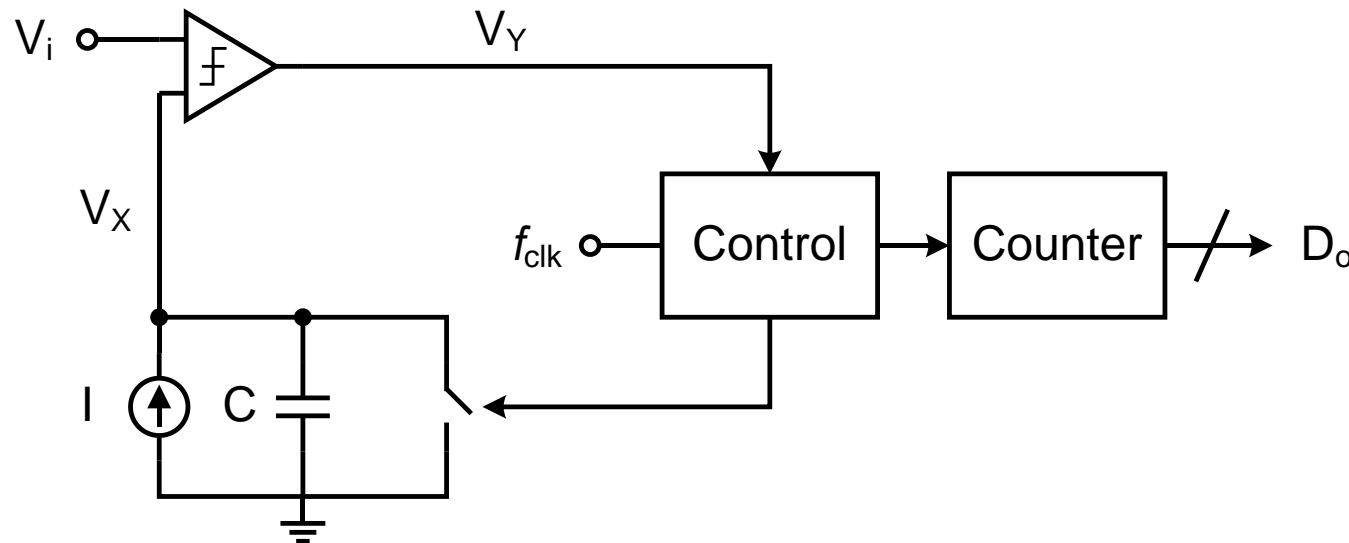
Kickback Noise

- ❑ Fixed comparator offsets in the SAR ADC show up as a tolerable signal offset that do not affect linearity
- ❑ But the use of dynamic comparators leads to strong kick-back
- ❑ The comparator decision will induce charge on the top plate that can affect the decision that is being processed or the next decision
 - Many designers avoid simple comparators (e.g., StrongArm)
 - Robust designs use preamplifiers
- ❑ In differential designs common-mode kick-back is cancelled

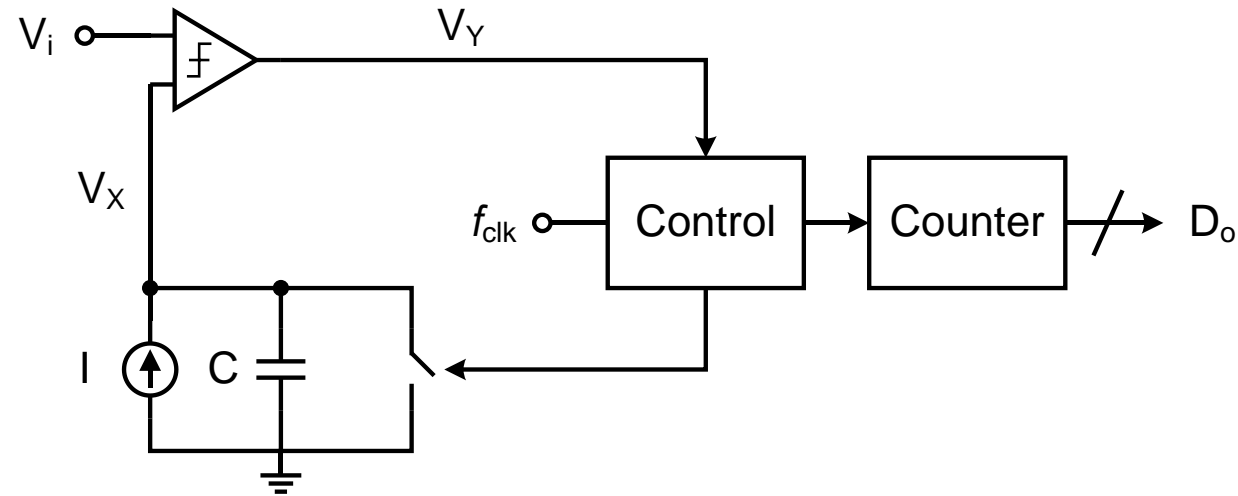


Single-Slope Integrating / Counting ADC

- ❑ Sampled-and-held input (V_i), linear search for output
- ❑ Counter keeps counting until comparator output toggles
 - Ramp signal generated by charging/discharging a capacitor with a constant current
 - Ramp linearity determines INL
- ❑ Simple, inherently monotonic, but very slow: $T_{conv} \sim 2^N \times T_{clk}$



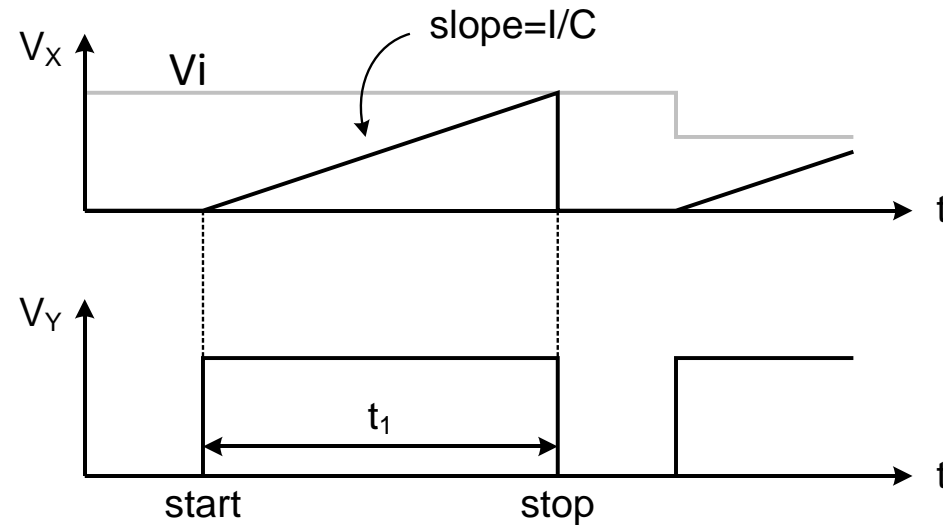
Single-Slope Integrating / Counting ADC



$$V_i = \frac{I}{C} \cdot t_1, \quad D_o = \left\lfloor \frac{t_1}{T_{\text{clk}}} \right\rfloor$$

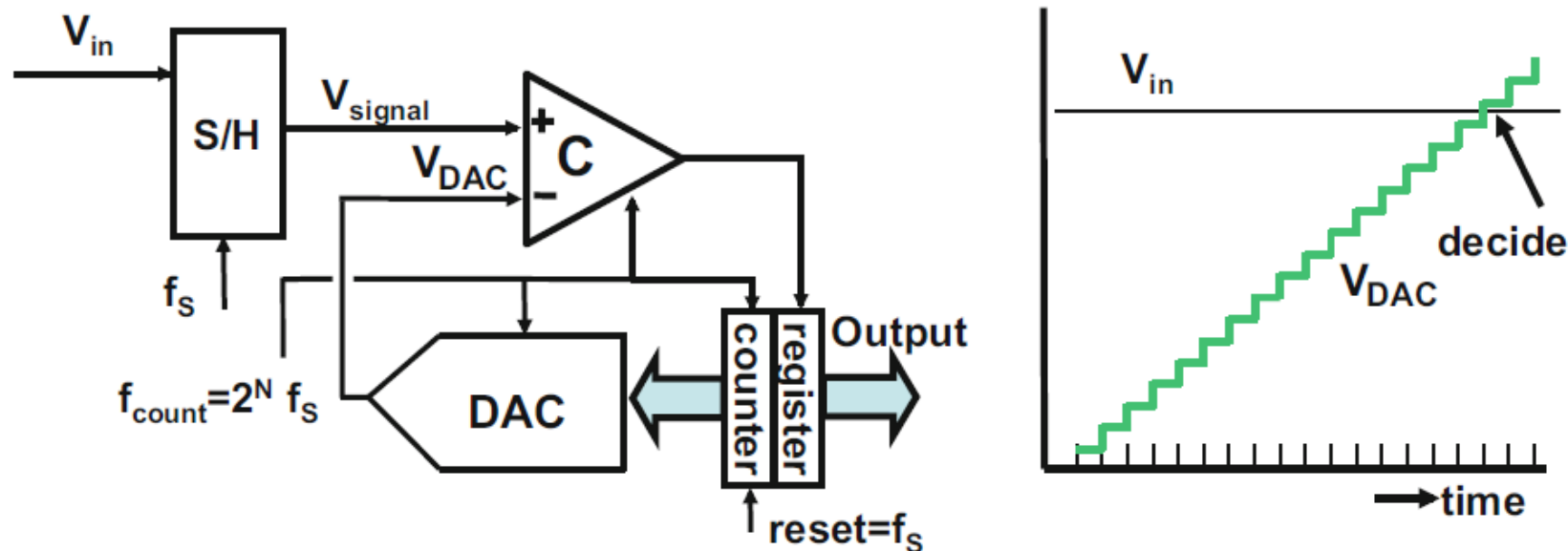
$$\Rightarrow D_o = \left\lfloor \frac{V_i}{\left(\frac{I \cdot T_{\text{clk}}}{C} \right)} \right\rfloor,$$

$$\text{LSB} = \frac{I \cdot T_{\text{clk}}}{C}$$



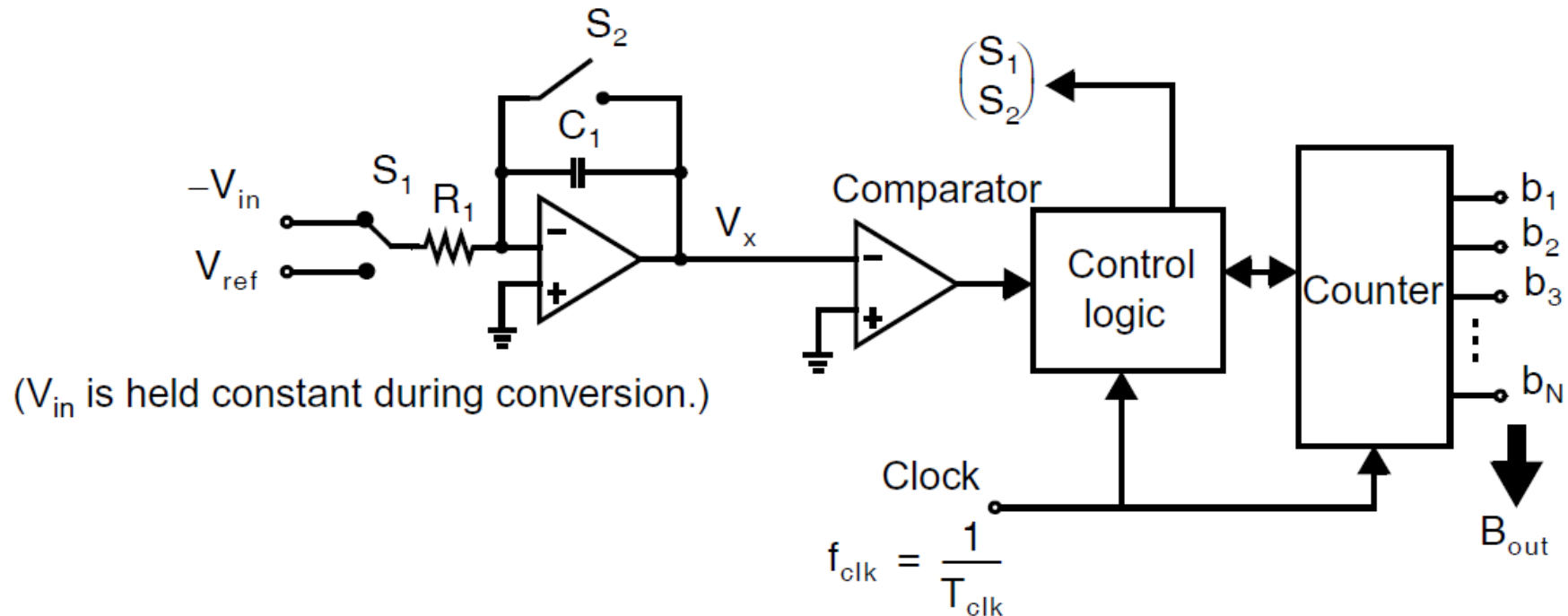
Single-Slope Integrating / Counting ADC

- ❑ For analog ramp
 - Need precision capacitor (C), current source (I), and clock (T_{clk})
- ❑ The ramp can be digitally generated using a DAC
 - Need precision DAC: DNL and INL depend on DAC ccs

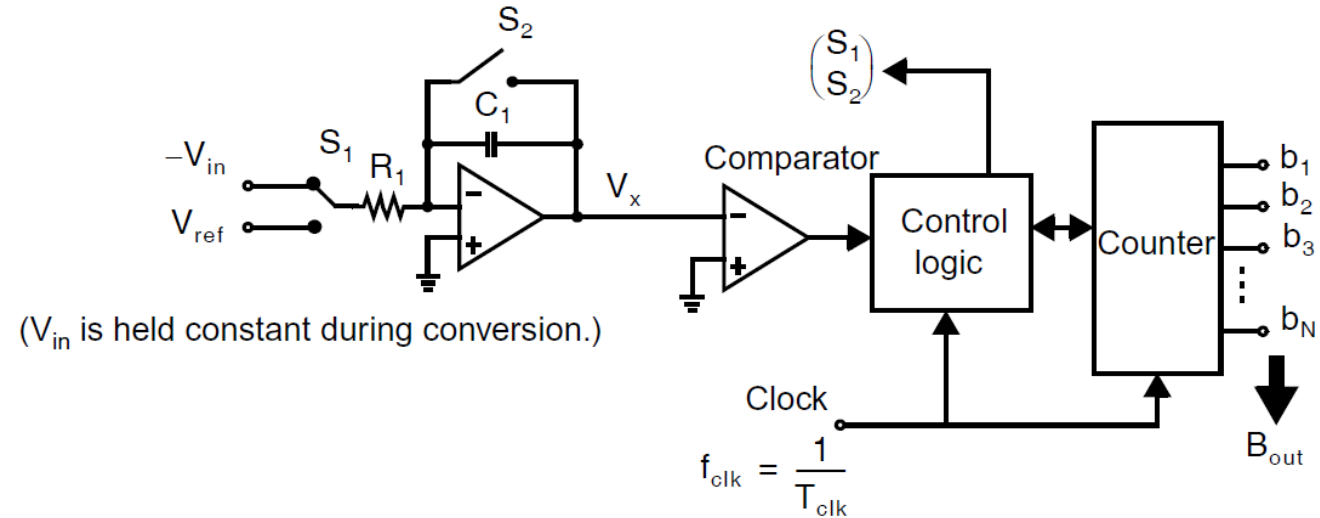


Dual-Slope Integrating ADC

- ❑ Op-amp converts V to I
 - Constant current is charging/discharging feedback capacitor
- ❑ Popular in multimeters and harsh industrial environments



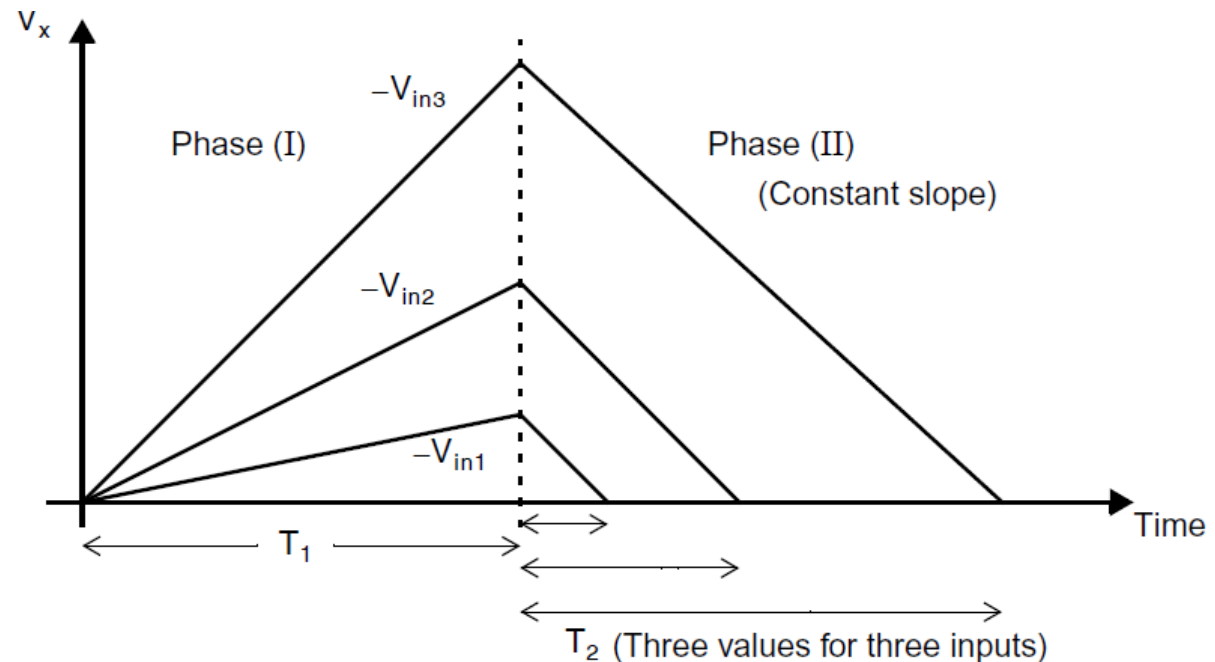
Dual-Slope ADC



$$V_m = \frac{V_i}{RC} \cdot t_1 = \frac{V_R}{RC} \cdot t_2$$

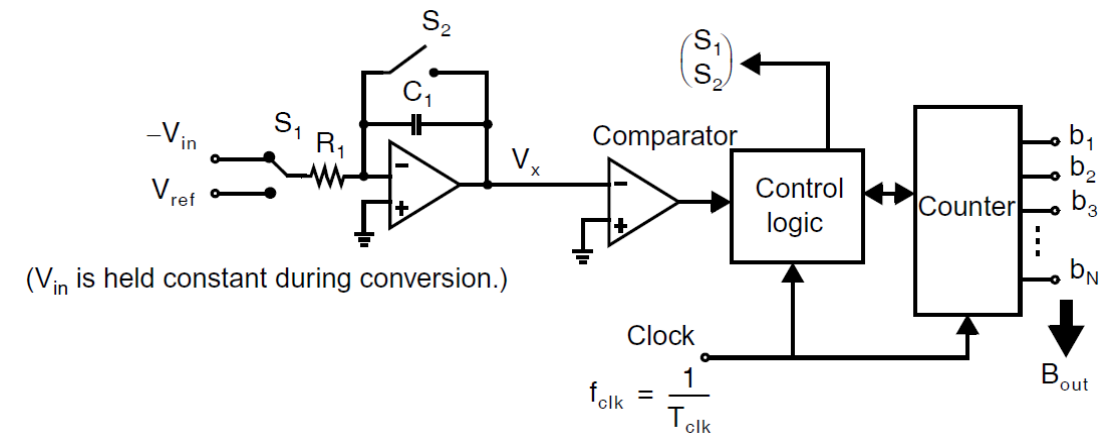
$$\Rightarrow D_o = \left\lfloor \frac{V_i}{V_R} \right\rfloor = \left\lfloor \frac{t_2}{t_1} \right\rfloor = \frac{N_2}{N_1}$$

or $D_o = N_2$ for fixed N_1



Dual-Slope ADC

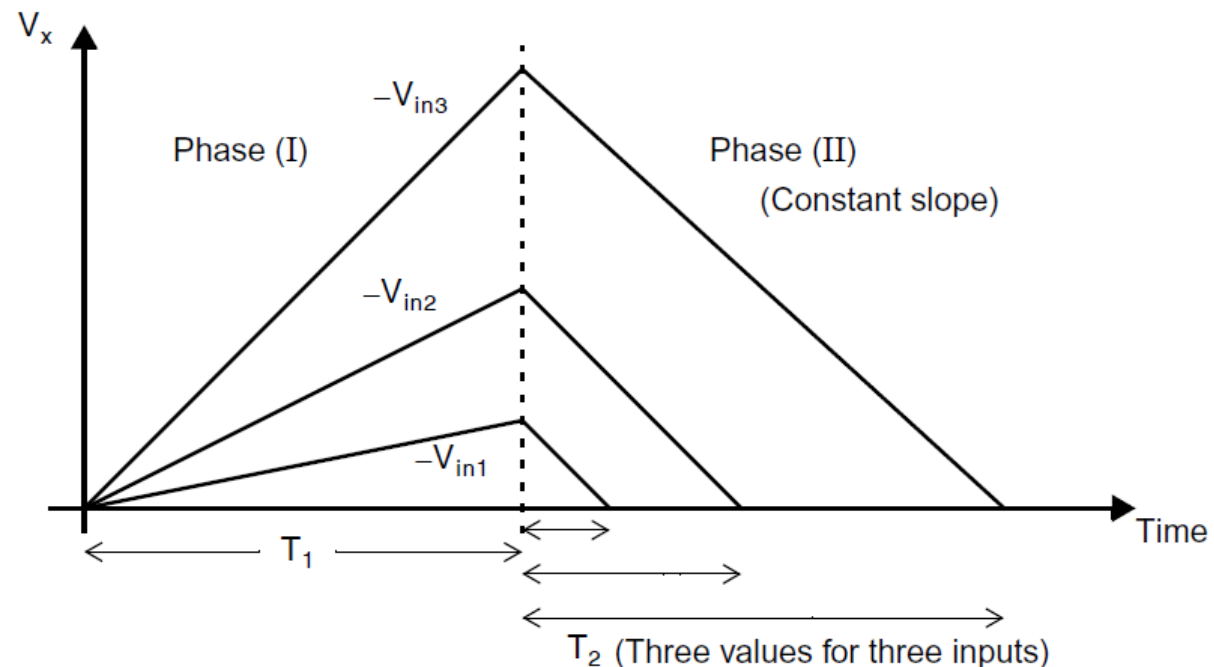
- ❑ Exact values of R , C , and T_{clk} are not required
- ❑ Comparator offset doesn't matter
- ❑ Op-amp offset introduces gain and offset error
- ❑ Op-amp nonlinearity introduces INL error



$$V_m = \frac{V_i}{RC} \cdot t_1 = \frac{V_R}{RC} \cdot t_2$$

$$\Rightarrow D_o = \left\lfloor \frac{V_i}{V_R} \right\rfloor = \left\lfloor \frac{t_2}{t_1} \right\rfloor = \frac{N_2}{N_1}$$

or $D_o = N_2$ for fixed N_1



References

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Thank you!